

74ABT541 Octal Buffer/Line Driver with 3-STATE Outputs

Features

- Non-inverting buffers
- Output sink capability of 64mA, source capability of 32mA
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50pF and 250pF loads
- Guaranteed simultaneous switching, noise level and dynamic threshold performance
- Guaranteed latchup protection

Ordering Information

- High-impedance, glitch-free bus loading during entire power up and power down cycle
- Nondestructive, hot-insertion capability
- Flow-through pinout for ease of PC board layout
- Disable time less than enable time to avoid bus contention

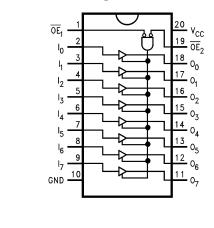
General Description

The ABT541 is an octal buffer and line driver with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus-oriented transmitter/receiver. The ABT541 is similar to the ABT244 with broadside pinout.

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Order Number	Package Number	Package Description
74ABT541CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74ABT541CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT541CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide
74ABT541CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Devices also available in Tape and Reel. Specify by appending suffix "X" to the ordering number. Pb-Free package per JEDEC J-STD-020B.

Connection Diagram



Pin Descriptions

Pin Names	Description
$\overline{OE}_1, \overline{OE}_2$	Output Enable Input (Active LOW)
I ₀ –I ₇	Inputs
O ₀ O ₇	Outputs

March 2007

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Truth Table

	Inputs				
OE ₁	OE ₂	I	Outputs		
L	L	Н	Н		
Н	Х	Х	Z		
Х	Н	Х	Z		
L	L	L	L		

H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

Z = High Impedance

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
T _{STG}	Storage Temperature	–65°C to +150°C
T _A	Ambient Temperature Under Bias	–55°C to +125°C
TJ	Junction Temperature Under Bias	–55°C to +150°C
V _{CC}	V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
V _{IN}	Input Voltage ⁽¹⁾	-0.5V to +7.0V
I _{IN}	Input Current ⁽¹⁾	-30mA to +5.0mA
Vo	Voltage Applied to Any Output	
	Disabled or Power-Off State	–0.5V to 5.5V
	HIGH State	-0.5V to V _{CC}
	Current Applied to Output in LOW State (Max.)	twice the rated I _{OL} (mA)
	DC Latchup Source Current	–500mA
	Over Voltage Latchup (I/O)	10V

Note:

1. Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Rating		
T _A	T _A Free Air Ambient Temperature			
V _{CC}	Supply Voltage	+4.5V to +5.5V		
$\Delta V / \Delta t$	Minimum Input Edge Rate			
	Data Input	50mV/ns		
	Enable Input	20mV/ns		

Symbol	P	arameter	V _{cc}	Conditions	Min.	Тур.	Max.	Units
V _{IH}	Input HIGH			Recognized HIGH Signal	2.0			V
V _{IL}	Input LOW	Voltage		Recognized LOW Signal			0.8	V
V _{CD}	Input Clam	p Diode Voltage	Min.	$I_{IN} = -18 \text{mA}$			-1.2	V
V _{OH}	Output HIG	GH Voltage	Min.	$I_{OH} = -3mA$	2.5			V
				$I_{OH} = -32mA$	2.0			V
V _{OL}	Output LO	N Voltage	Min.	$I_{OL} = 64 \text{mA}$			0.55	V
I _{IH}	Input HIGH	I Current	Max.	$V_{IN} = 2.7V^{(3)}$			1	μA
				$V_{IN} = V_{CC}$			1	
I _{BVI}	Input HIGH Breakdown		Max.	V _{IN} = 7.0V			7	μA
IIL	Input LOW Current		Max.	$V_{IN} = 0.5V^{(3)}$			-1	μA
				$V_{IN} = 0.0V$			-1	1
V _{ID}	Input Leakage Test		0.0	$I_{ID} = 1.9\mu A$, All Other Pins Grounded	4.75			V
I _{OZH}	Output Leakage Current		0–5.5V	$V_{OUT} = 2.7V, \overline{OE}_n = 2.0V$			10	μA
I _{OZL}	Output Lea	kage Current	0–5.5V	$V_{OUT} = 0.5V, \overline{OE}_n = 2.0V$			-10	μA
I _{OS}	Output Sho	ort-Circuit Current	Max.	$V_{OUT} = 0.0V$	-100		-275	mA
I _{CEX}	Output HIG Current	GH Leakage	Max.	V _{OUT} = V _{CC}			50	μA
I _{ZZ}	Bus Draina	ige Test	0.0	V _{OUT} = 5.5V, All Others GND			100	μA
I _{CCH}	Power Sup	ply Current	Max.	All Outputs HIGH			50	μA
I _{CCL}	Power Sup	ply Current	Max.	All Outputs LOW			30	mA
I _{CCZ}	Power Sup	ply Current	Max.	$\overline{OE}_n = V_{CC}$, All Others at V_{CC} or Ground			50	μA
I _{CCT}	Additional	Outputs Enabled		$V_{I} = V_{CC} - 2.1V$			2.5	mA
	I _{CC} /Input	Outputs 3-STATE	Max.	Enable Input $V_I = V_{CC} - 2.1V$			2.5	mA
	Outputs 3-STATE			Data Input $V_I = V_{CC} - 2.1V$, All Others at V_{CC} or Ground			50	μA
I _{CCD} Dynamic I _{CC} No Load ⁽³⁾		Max	Outputs Open, $\overline{OE}_n = GND$, One-Bit Toggling ⁽²⁾ , 50% Duty Cycle			0.1	mA/ MHz	

Notes:

2. For 8-bit toggling, $I_{CCD} < 0.8 \text{mA/MHz}.$

3. Guaranteed, but not tested.

3

DC Electrical Characteristics

SOIC package.

			Conditions C _L = 50pF,				
Symbol	Parameter	V _{cc}	$R_L = 500\Omega$	Min.	Тур.	Max.	Units
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	5.0	$T_A = 25^{\circ}C^{(4)}$		0.7	1.0	V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	5.0	$T_A = 25^{\circ}C^{(4)}$	-1.3	-0.8		V
V _{OHV}	Minimum HIGH Level Dynamic Output Voltage	5.0	$T_A = 25^{\circ}C^{(5)}$	2.7	3.1		V
V _{IHD}	Minimum HIGH Level Dynamic Input Voltage	5.0	$T_A = 25^{\circ}C^{(6)}$	2.0	1.4		V
V _{ILD}	Maximum LOW Level Dynamic Input Voltage	5.0	$T_A = 25^{\circ}C^{(6)}$		1.1	0.6	V

Notes:

4. Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

5. Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

6. Max number of data inputs (n) switching. n – 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold (V_{ILD}). Guaranteed, but not tested.

AC Electrical Characteristics

SOIC and SSOP package.

		T _A = +25°C, V _{CC} = +5V, C _L = 50pF		$T_A = -40^{\circ}C$ $V_{CC} = 4.$ $C_L =$			
Symbol	Parameter	Min.	Тур.	Max.	Min.	Max.	Units
t _{PLH}	Propagation Delay,	1.0	2.0	3.6	1.0	3.6	ns
t _{PHL}	Data to Outputs	1.0	2.4	3.6	1.0	3.6	
t _{PZH}	Output Enable Time	1.5	3.1	6.0	1.5	6.0	ns
t _{PZL}		1.5	3.7	6.0	1.5	6.0	
t _{PHZ}	Output Disable Time	1.7	3.5	6.1	1.7	6.1	ns
t _{PLZ}		1.7	3.1	5.6	1.7	5.6	

Extended AC Electrical Characteristics

SOIC package.

		-40°C to +85°C, V _{CC} = 4.5V to 5.5V, C _L = 50pF, 8 Outputs Switching ⁽⁷⁾		V _{CC} = 4.5 C _L = 2 1 Οι	C to +85°C, V to 5.5V, 250pF, Itput hing ⁽⁸⁾				
Symbol	Parameter	Min.	Тур.	Max.	Min.	Max.	Mi.n	Max.	Units
ftoggle	Max Toggle Frequency		100						MHz
t _{PLH}	Propagation Delay,	1.5		5.0	1.5	6.0	2.5	8.5	ns
t _{PHL}	Data to Outputs	1.5		5.0	1.5	6.0	2.5	8.5	
t _{PZH}	Output Enable Time	1.5		6.5	2.5	7.5	2.5	9.5	ns
t _{PZL}		1.5		6.5	2.5	7.5	2.5	10.5	
t _{PHZ}	Output Disable	1.0		6.1	(1	0)			ns
t _{PLZ}	Time	1.0		5.6					

Notes:

7. This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

- This specification is guaranteed but not tested. The limits represent propagation delay with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load. This specification pertains to single output switching only.
- This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.
- 10. The 3-STATE delays are dominated by the RC network (500 Ω , 250pF) on the output and have been excluded from the datasheet.

Skew

SOIC package.

		$\label{eq:TA} \begin{array}{l} \textbf{T}_{A} = -40^{\circ}\text{C to } +85^{\circ}\text{C}, \\ \textbf{V}_{CC} = 4.5\text{V to } 5.5\text{V}, \\ \textbf{C}_{L} = 50\text{pF}, \\ 8 \text{ Outputs} \\ \text{Switching}^{(11)} \end{array}$	$\begin{array}{l} T_{A} = -40^{\circ}\text{C to } +85^{\circ}\text{C}, \\ V_{CC} = 4.5\text{V to } 5.5\text{V}, \\ C_{L} = 250\text{pF}, \\ 8 \text{ Outputs} \\ \text{Switching}^{(12)} \end{array}$	
Symbol	Parameter	Max.	Max.	Units
t _{OSHL} ⁽¹³⁾	Pin to Pin Skew, HL Transitions	1.3	2.3	ns
t _{OSLH} ⁽¹³⁾	Pin to Pin Skew, LH Transitions	1.0	1.8	ns
t _{PS} ⁽¹⁴⁾	Duty Cycle, LH/HL Skew	2.0	3.5	ns
t _{OST} ⁽¹³⁾	Pin to Pin Skew, LH/HL Transitions	2.0	3.5	ns
t _{PV} ⁽¹⁵⁾	Device to Device Skew, LH/HL Transitions	2.0	3.5	ns

Notes:

11. This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.)

- 12. These specifications guaranteed but not tested. The limits represent propagation delays with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.
- 13. Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW (t_{OSHL}), LOW-to-HIGH (t_{OSLH}), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW (t_{OST}). The specification is guaranteed but not tested.
- 14. This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.
- 15. Propagation delay variation for a given set of conditions (i.e., temperature and V_{CC}) from device to device. This specification is guaranteed but not tested.

Capacitance

Symbol	Parameter	Conditions T _A = 25°C	Тур.	Units
C _{IN}	Input Capacitance	$V_{CC} = 0.0V$	5.0	pF
C _{OUT} ⁽¹⁶⁾	Output Capacitance	$V_{CC} = 5.0V$	9.0	pF

Note:

16. C_{OUT} is measured at frequency of f = 1 MHz, per MIL-STD-883, Method 3012.

AMP (V)

AMP (V)

0١

٥٧

90%

10%

10%

90%

AC Loading +7V OPEN 90% NEGATIVE ALL OTHER PULSE t_{PZL}, t_{PLZ} 10% tf 500Ω D.U.T. 90% POSITIVE PULSE 500Ω 50 pF 10% = 1.5V Vм

*Includes jig and probe capacitance

Figure 1. Standard AC Test Load



Amplitude	Rep. Rate	t _W	t _r	t _f
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

Figure 3. Test Input Signal Requirements

AC Waveforms

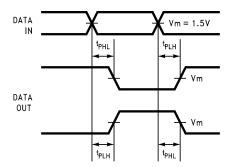
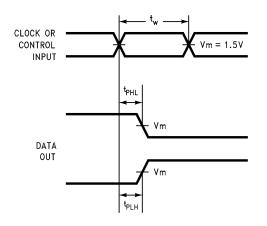
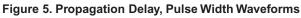


Figure 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions





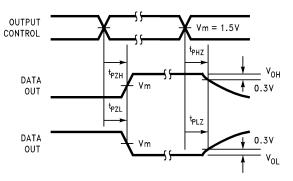
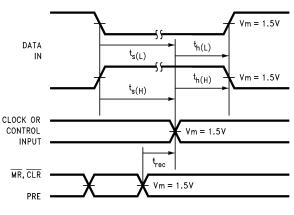


Figure 2. Test Input Signal Levels

Figure 6. 3-STATE Output HIGH and LOW Enable and Disable Time

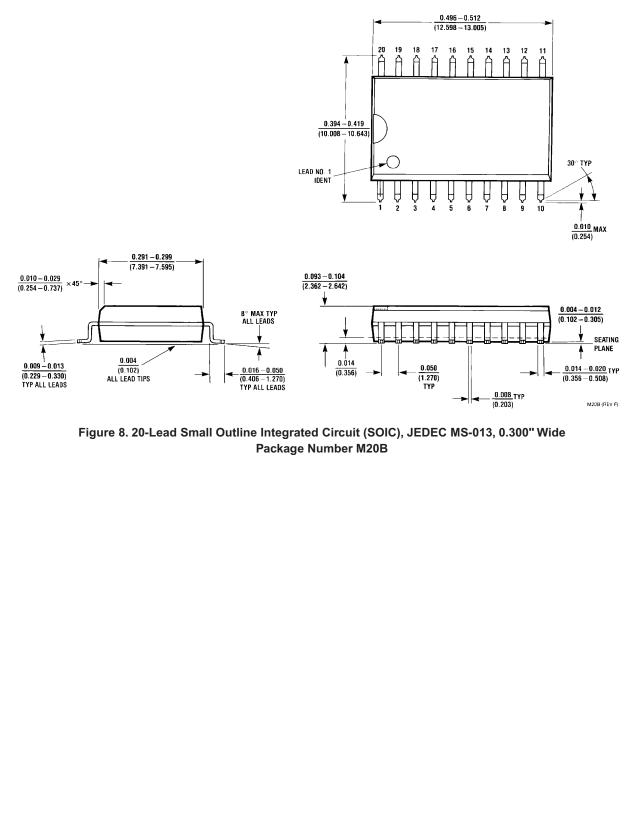


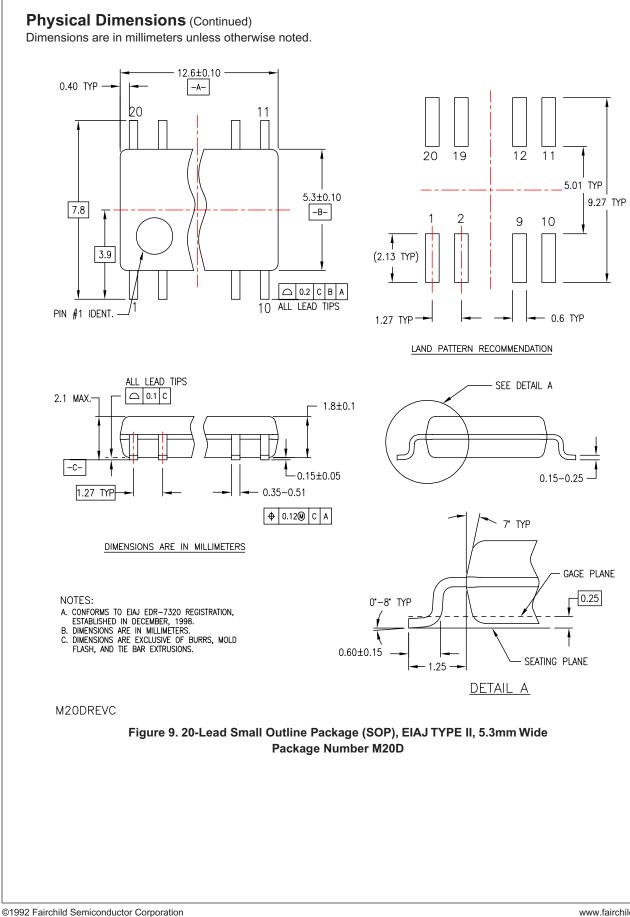


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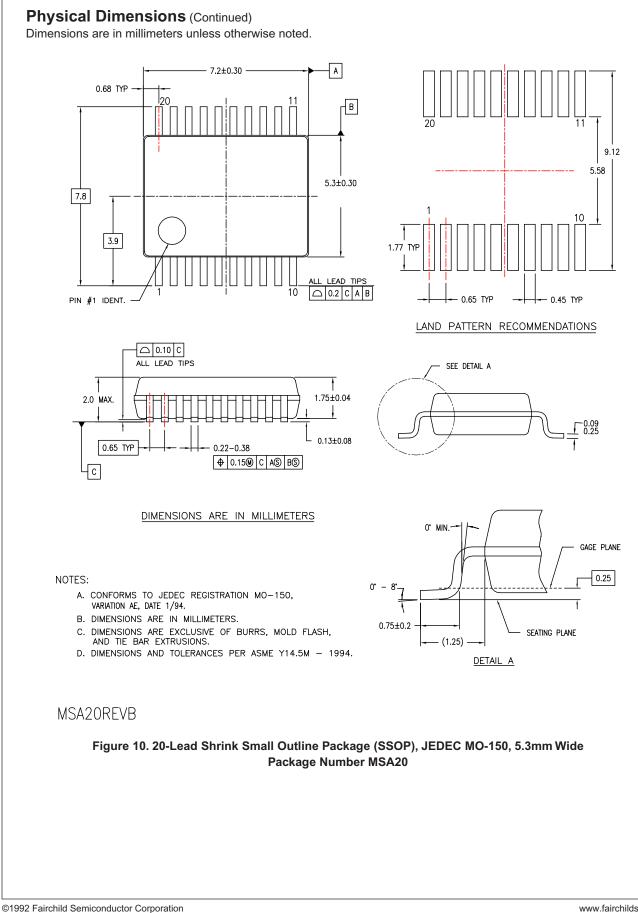


Dimensions are in inches (millimeters) unless otherwise noted.

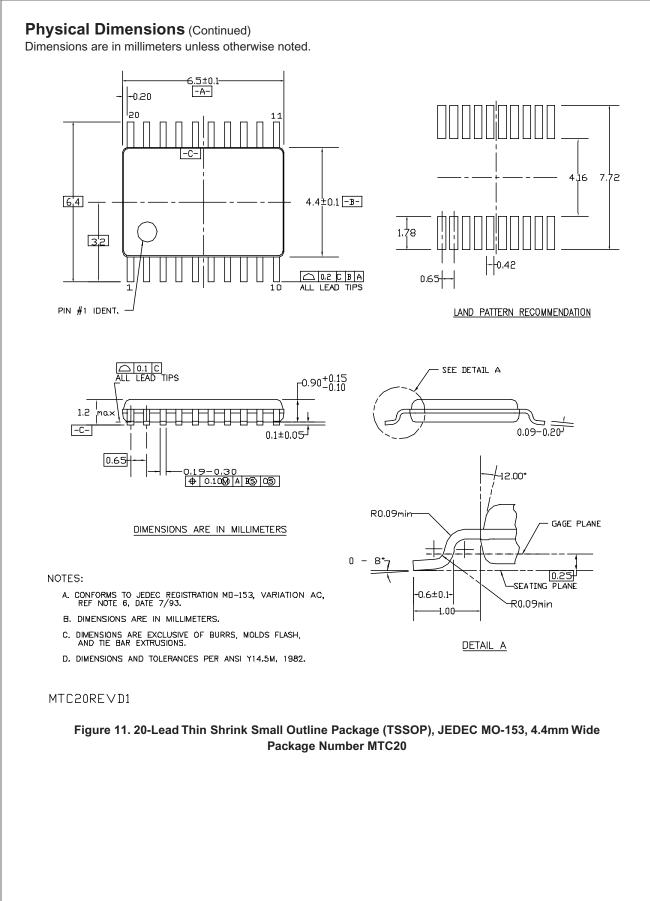




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